

PE-xxxx  
Revision B

WS1050 MEMS CYCLING AND HOLD DOWN

TEST PROCEDURE

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# Purpose and Scope

## Purpose

This document defines the procedures and requirements for cycling and continuous hold down stresses for MEMS tunable capacitors.

## Scope

This procedure applies to the qualification and ongoing production monitoring of WS1050.

# Responsibilities

The Product Engineering function is responsible for assuring compliance to the requirements of this document.

# REFERENCE DOCUMENTS

|  |  |
| --- | --- |
| Document No. | Document Name |
| PE-0002 | Equipment Calibration Procedure |

Table 1 Reference Document List

# FORMS

|  |  |
| --- | --- |
| Form No. | Form Name |
|  |  |

Table 2 Form List

# DEFINITIONS (Not Applicable)

# EQUIPMENT AND MATERIALS

Equipment consists of:

|  |  |  |  |
| --- | --- | --- | --- |
| **Item** | **Model** | **Manufacturer** | **Comments** |
| Computer (equipment controller) | PC with Window XP, 7 | Any |  |
| Software (equipment controller) | LabView 2012 or Higher |  |  |
| GPIB-USB-HS | 778927-01 | National Instruments |  |
| Triple Output Power Supply | E3631A | Agilent/Keysight | w/ GBIP interface |
| Source Meter | 2400 | Keithley | w/ GBIP interface |
| DMM | 2000 | Keithley | w/GPIB interface |
| FPGA | PIX-7813R | National Instruments |  |
| PXI Card Chassis | PIX-1033 | National Instruments |  |
| DUT boards | Various**1** | --- | WiSpry Design |
| SHC68-68-RDIO Shielded Cable | 191667-01 | National Instruments | NI Cables |

Table 3 MEMS Reliability Stress Stand Equipment List

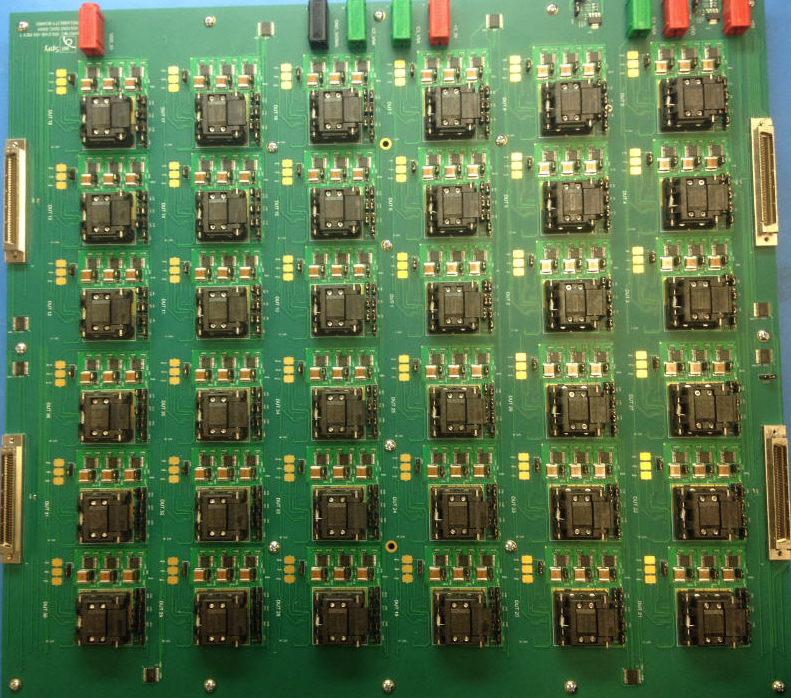
Notes:

**1** WS1050 board is 36 positions (model WS-EVB-165)

# REQUIREMENTS AND PROCEDURES

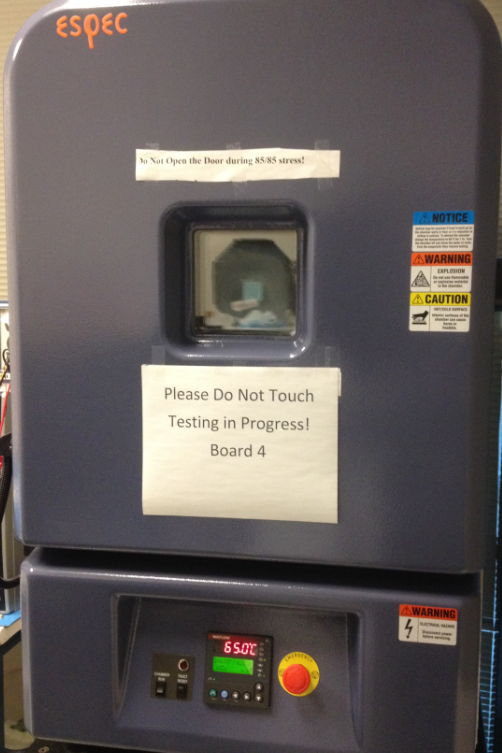
## Basic Hardware, Software, and Environmental Requirements

* + 1. Cycling and hold down hardware (boards, cables, connectors, bench equipment) must be able to:
       1. Meet the electrical conditions specified in sections 7.2 and 7.3.
       2. Meet WiSpry calibration requirements specified in PE-0002.
       3. Be sufficiently robust to ensure minimum leakage currents.



Picture 36 DUT Board

* + 1. Cycling and hold down software should:
       1. Allow for insitu monitoring for stiction events.
       2. Meet the electrical conditions specified in sections 7.2 and 7.3.
    2. Cycling and hold down environmental controls shall:
       1. Provide control of temperature and humidity.
          1. The ESPEC where we can control the temperature and humidity

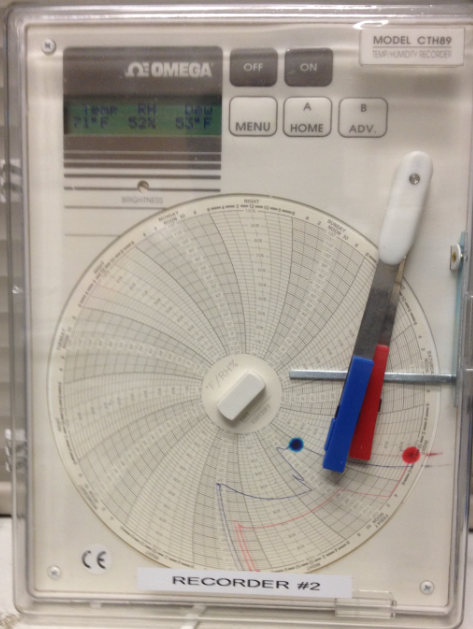


Picture 1 the ESPEC Oven Controls Temperature and Humidity

* + - * 1. Yamato ovens where we control temperature, not humidity. But lab humidity is monitored by using OMEGA model CTH89



Picture 2 the Yamato Oven Controls Temperature



Picture 3 the OMEGA Monitors the Lab Humidity

* + - 1. Meet calibration requirements defined in PE-0002.

## MEMS Switch Cycling Stress

The cycling conditions for product qualification and ongoing monitoring are:

|  |  |
| --- | --- |
| **Stress Condition** | **Requirement** |
| MEMS Operating Voltage (VOP) | 44 V |
| VDD | 3.7 V |
| Temperature | 25 oC, 45 oC , 65 oC , typical 65 oC |
| Frequency | 12 KHz |
| Duty Cycle | 25% |
| Dual Voltage Actuation (DVA) | ON or OFF, typical OFF |
| Beam Actuation | All beams cycles simultaneously |
| Beam Read Points | 0, 2K, 10K, 100K, 1M, 5M, 10M, 20M, 30M … TTF |
| Test Sequence | In series: Bank 1, Bank 2, then Bank 3 |

Table 4 MEMS Switch Cycling Stress Conditions for Product Qualification

## MEMS Continuous Hold Down Stress

The continuous hold down conditions for product qualification and ongoing monitoring are:

|  |  |
| --- | --- |
| **Stress Condition** | **Requirement** |
| MEMS Operating Voltage (VOP) | 44 V |
| VDD | 3.3 V |
| Temperature | 25 oC, 45 oC , 65 oC , typical 65 oC |
| Frequency | ---- |
| Duty Cycle | 100% |
| Dual Voltage Actuation (DVA) | ON or OFF, typical OFF |
| Beam Actuation | All beams cycles simultaneously and held for the stress duration |
| Beam Read Points | 0, 5m, 10m, 15m, 30m, 45m, 60m, 90m … 5h, 6h, 7h … TTF |
| Test Sequence | In series: Bank 1, Bank 2, then Bank 3 |

Table MEMS Continuous Hold down Stress Conditions for Product Qualification

## General Set-up and Handling Guidelines

### Device Under Test (DUT) should be handled according to class 1 procedure (ESD)

### After loading part onto board, let the parts soak at temperature prior to starting stress test. Recommend a minimum temperature stabilization soak of 30 minutes.

### Preconditioning of new stress boards (to remove excess absorbed moisture), 24 hour bake at 85C

### Socket inspection after each run and cleaning/repair as required

## Test Set-up Procedure

* + 1. Figure 1 shows the test set-up block diagram for WS1050 Reliability Test, Multi DUT.
       1. Using banana plug cables to connect all test equipments as in Figure 1.
       2. For power supply E3631A, use channel 1 for VDD, channel 2 for +3.3V.



Figure 1 MEMS Cycling and Hold down Reliability Stress Test Set-Up Block Diagram



Picture 4 MEMS Cycling and Hold down Reliability Stress Test Set-Up

* + 1. Figure 2 shows the front panel of the test program (for the WS1050 version 1.5)
    2. Contact WiSpry Engineering for the latest version of the test program.
    3. Test programs are located in directory: S:\Software\_Control\Released\36 DUT Board

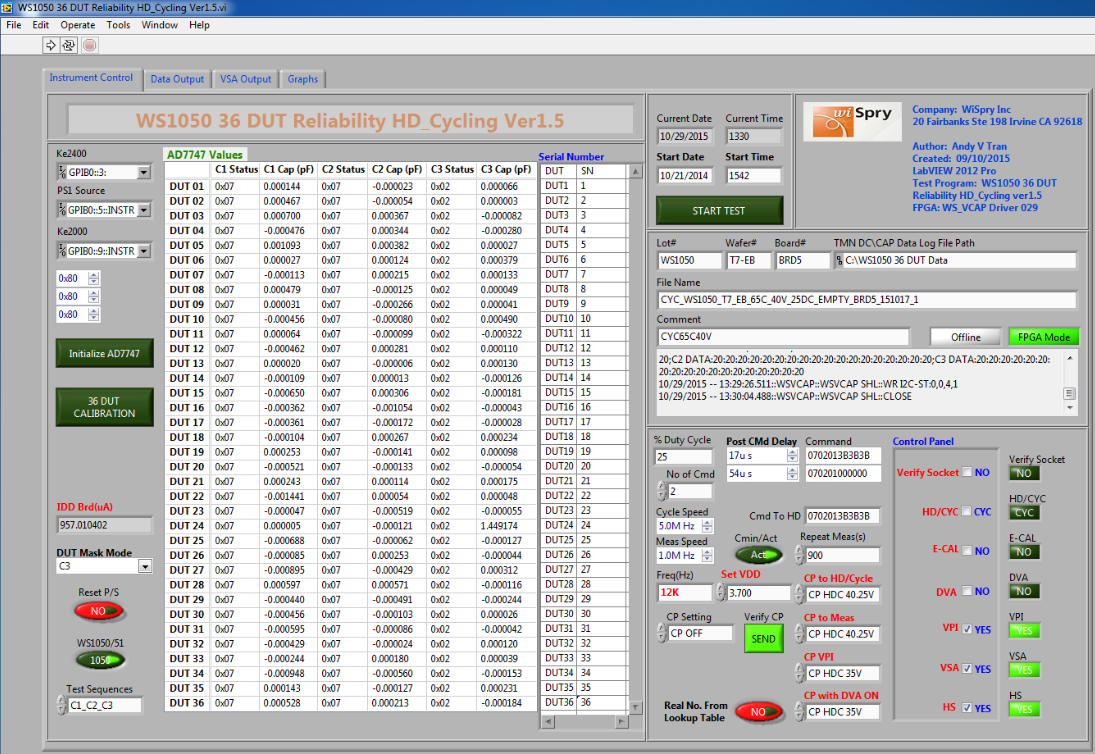


Figure 2 Front Panel of the WS1050 36 DUT Stress Test Program

## Test Operating Procedure

* + 1. Set temperature to meet requirement (25C, 45C, 65C)
    2. Set-up test program
* From labVIEW test program (Figure 2) click  this button at the top left corner to run the test program, it will pop-up a dialog box (Figure 3) below to ask the look up table for read point

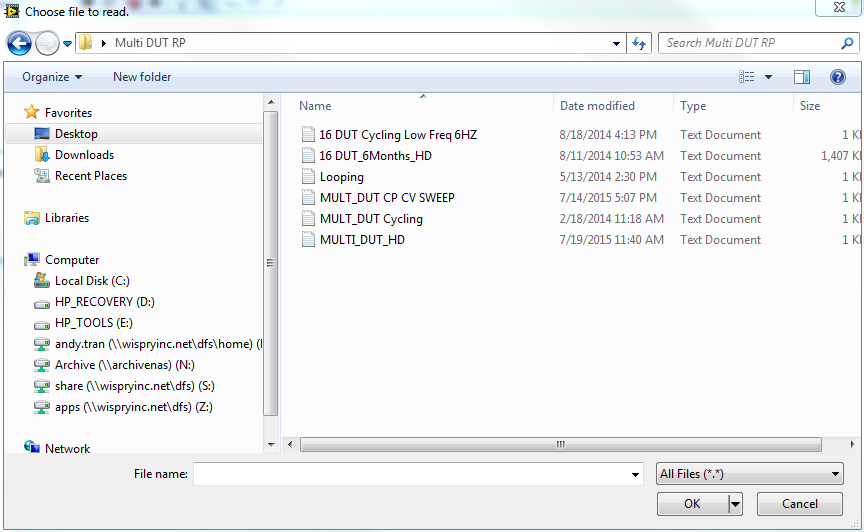


Figure 3 Share Drive Folder for Multi-DUT Cycling or HD Read Point Definition

* Select the correct Read Point file depending on the stress being run;
  + Select **MULT\_DUT Cycling** for cycling test

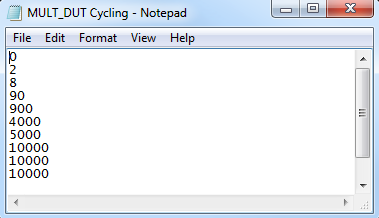


Figure Cycling Read Point

* + Select **MULT\_DUT HD** for hold down test

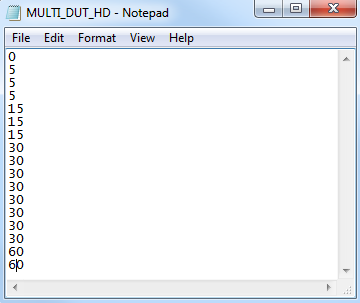


Figure Hold down Read Point

* For calibration (Figure 6): All sockets should be empty and the capacitance values of 36 DUT should be around zeros “~0.0001”for all three banks. If not, click on “36 DUT CALIBRATION” button to calibrate the sockets
* Insert DUTs into sockets and monitor COFF for a contact issue, DUT will be inserted start from DUT1 to DUT36 are labeled on the board.

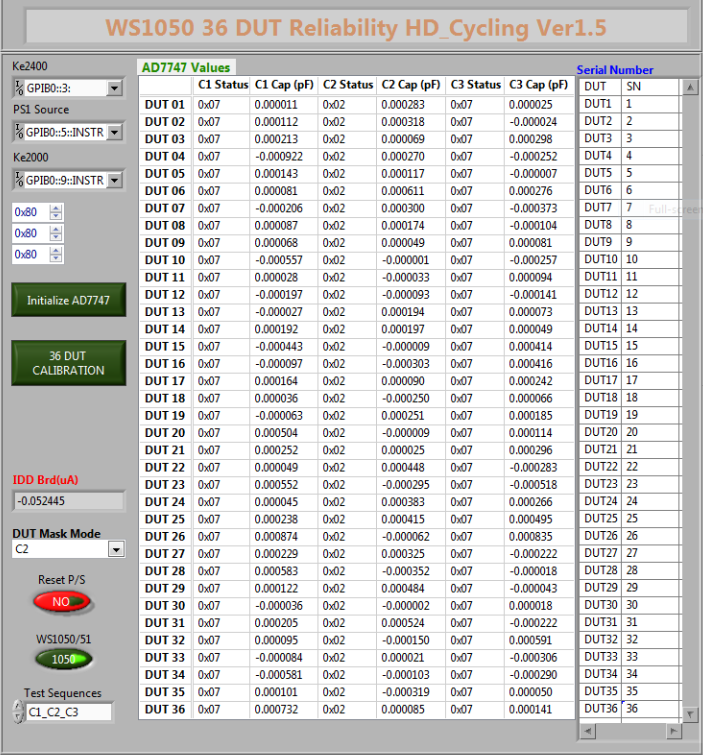


Figure 6 Empty Socket Calibration Summary Window

Note: If sockets are not zeros “~0”, click on “Initialize AD7747” button  to initialize the ADI chip, make sure the capacitance values will be less than 1pF (<1pF) for all three banks of 36 DUT, click on “36 DUT CALIBRATION” button to zero out the sockets.

* Set-up test condition: The front panel (Figure 7) was set by default with cycling, DVA OFF, E-CAL OFF, VPI ON, VSA ON, HS = ON, VDD = 3.7V, cycle speed = 12 KHz, CP stress = 40.25V

# 

Figure 7 Test Condition Set-Up Front Panel for default cycling conditions (DVA = OFF, ECAL = OFF, VPI = ON, HS (Handshake) = ON, Duty Cycle = 25%, VDD = 3.7V, Frequency = 12 KHz, Charge Pump = 40.25V, Charge Pump VPI = 35V

* Verify Socket: This run is required for the first set up with the new board to verify the board is stable before stressing devices, and the reading point will depend on “Repeat Meas(s)” set up.
* HD/CYC: Select this box to run Hold down Stress or Cycling Stress
* E-CAL: Select this box to run a stress with E-CAL ON or OFF
* DVA: Select this box to run a stress with Dual Voltage Actuation ON or OFF
* VPI: Select this box to decide to run with a voltage pull in. This will help to monitor all the beam closed completely (by bank) based on the capacitance values for each read point
* VSA: Select this box if decide to run a stress with a Voltage Self Actuation Test (by bank)
* HS: Select this box to run the handshake check to verify the contact issue and read back EFUSE
* Set-up with standard stress (cycle): All Drivers ON, All Drivers OFF, 25% Duty. All numbers should be set as same as the boxes are shown below**:**

# 

Figure 8 All Drivers ON and All Drivers OFF Set Up Box for 25% Duty Cycle. The numbers in the command box should be represented as shown

* Set-up with special stress (cycle): C1 ON, C2 OFF, C3 OFF; C1 OFF, C2 ON, C3 OFF; C1 OFF, C2 OFF, C3 ON, 33% Duty. Make sure all the numbers will be set as same as the boxes are shown below:

# 

Figure 9 Special Cycling Stress Test Set-Up with 33% duty cycle. Note: Commands numbers must be as shown in the Figure

* Set-up for stress (Hold Down): All Drivers should be closed during hold down, 100% duty, this was set by default



Figure 10 Stress Test Control Set Up for Conditions Hold Down. Note: Commands numbers must be as shown in the Figure

* Figure 11 shows the front panel is set-up to collect the test data.

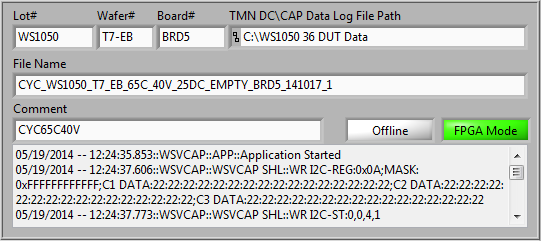


Figure 11 Front Panel to Set Up Data Collection

Note: The file name format will be:

**stress\_lot#\_wafer#\_design\_temperature\_CPV Stress\_duty\_brd#\_yymmdd\_run**

* The test can be set to start immediately by clicking on the START TEST button; alternatively the start date and time can be programmed as shown in Figure 12.

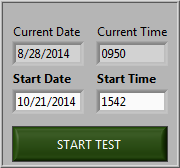


Figure 12 Cycling or Hold down Stress Initiation for immediate or delayed start

**Note:** **The time shall be set at least 30 minutes to wait after loading parts to the board in the oven/chamber. This time is required for the stabilization of the board dwell time at the temperature before to run stress.**

* The front panel (Figure 13) displays the capacitance values, number of cycles or times during stress

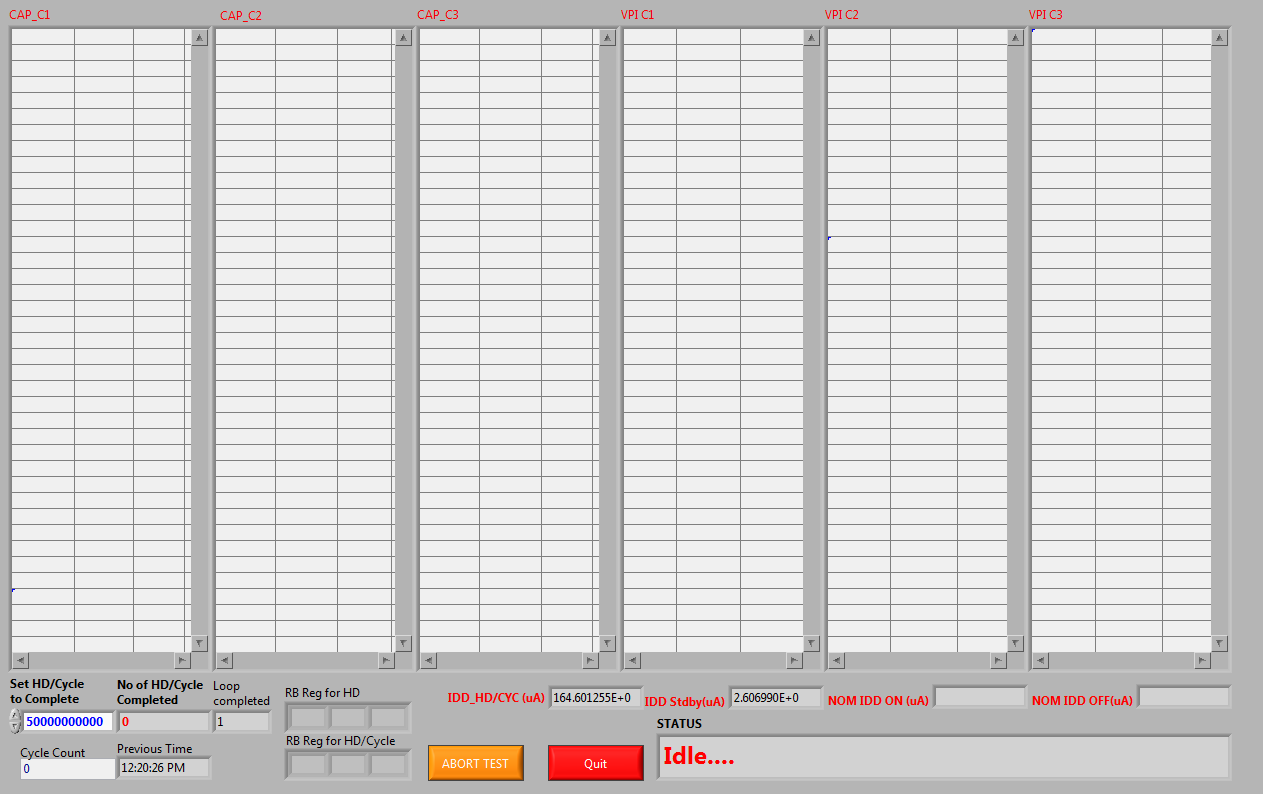


Figure 13 This Front Panel will display the capacitance values at every read point

* The front panel (Figure 14) displays VSA, HS check, EFUSE, % Delta CAP for every read point

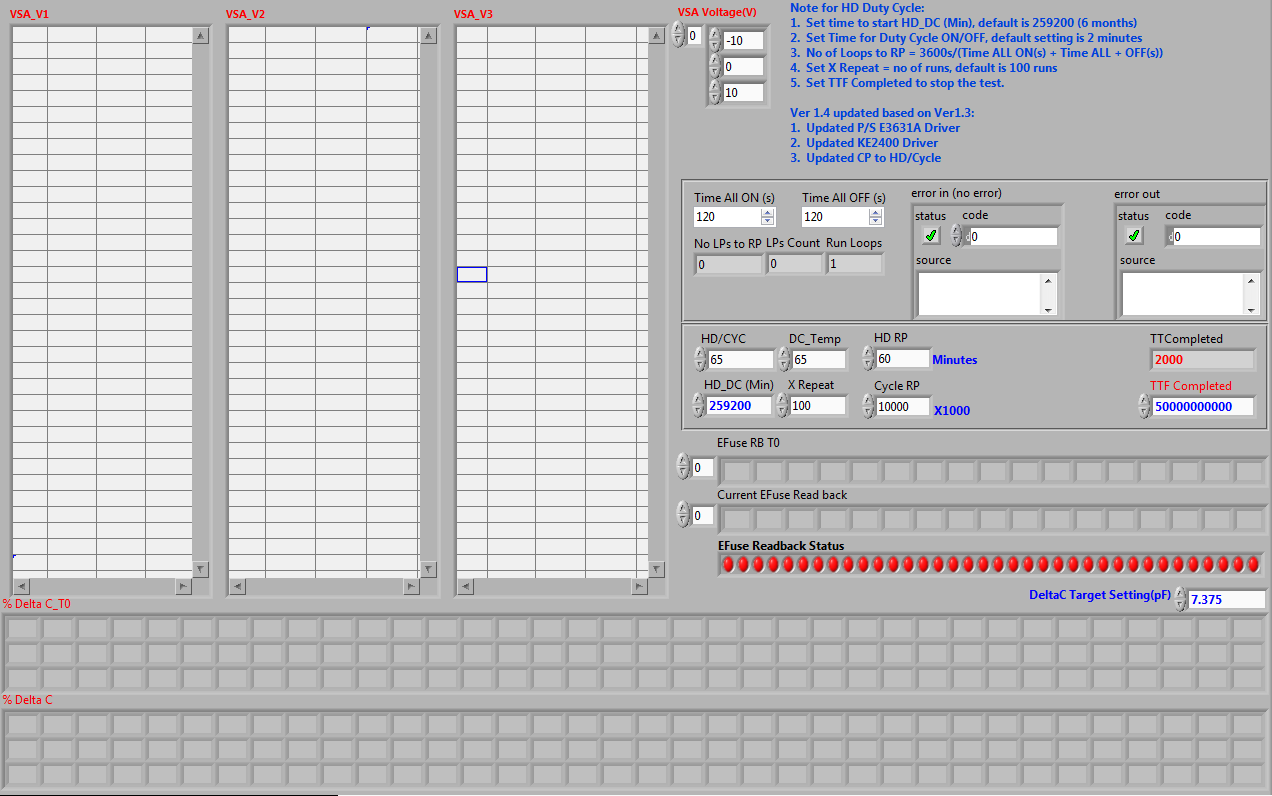


Figure 14 the Front Panel shown will display the VSA, HS check, EFUSE, %Delta CAP for every read point

* Figure 15 shows the output results, so that changes in COFF can be monitored during stress.

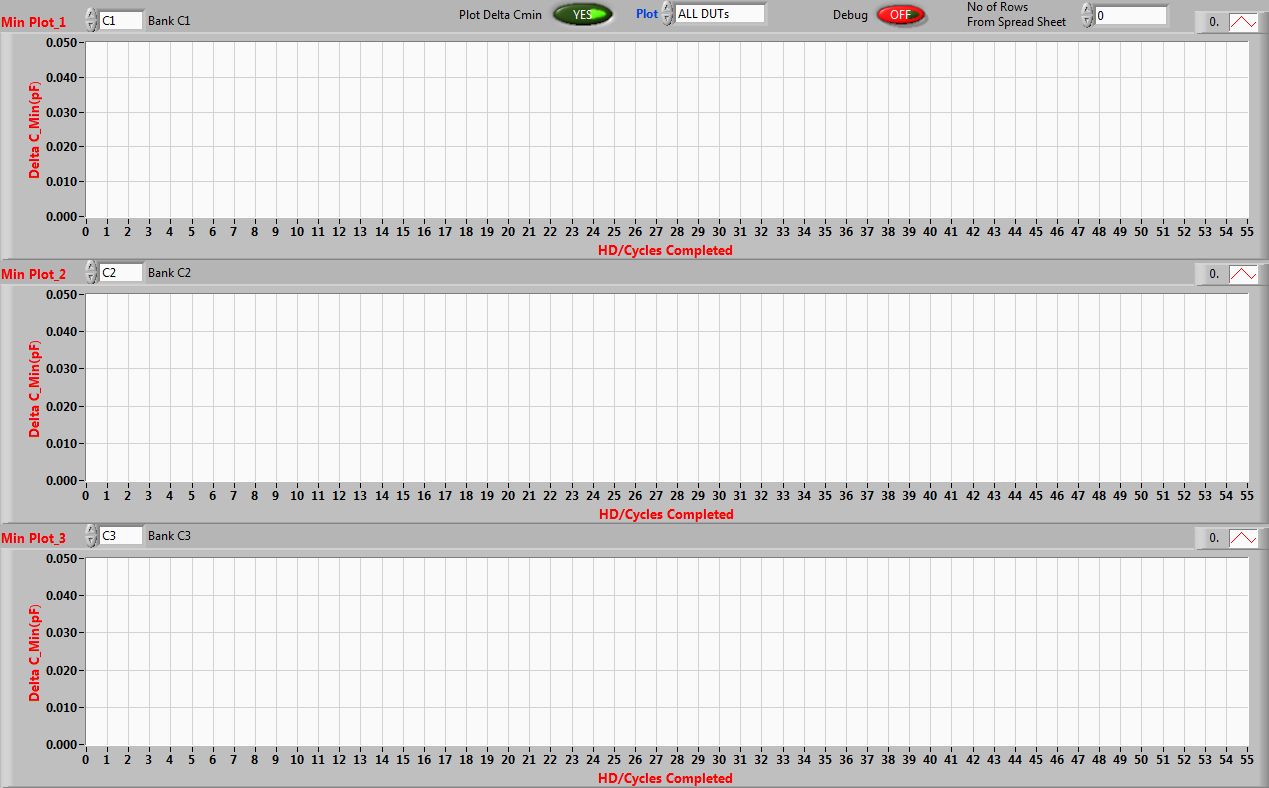


Figure 15 This shows the Output results for monitoring the instantaneous changes in COFF

* Stop stress or abort the test: The test can be aborted immediately by click on the ABORT TEST button (Figure 16) or enter the number that will be set to complete the test (5 billion cycles was set by default).

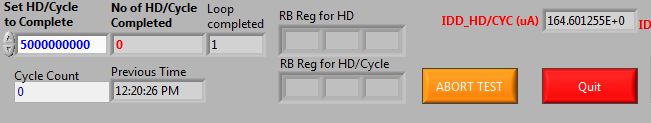


Figure 16 This Front Panel can be used to ABORT the stress or to set the minimum number of cycles to achieve. The button ABORT TEST will abort the stress

* This is a special test for Hold down during cycle test.
* The standard Hold down depends on the number set up from the box “HD\_DC (min)”, (259200 min = 6 months is set by default).
* When the number from “Set HD/Cycle to Completed” = “HD\_DC (min)” then the next run will be two minutes ON (turn All Drivers ON), two minutes OFF (turn All Drivers OFF)

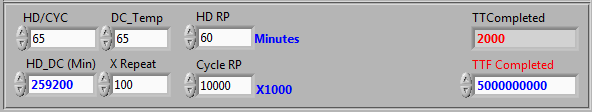


Figure 17 This Front Panel can be used for Hold down during cycle test.

# REVISION HISTORY

|  |  |  |  |
| --- | --- | --- | --- |
| Rev | Description | Editor | Date |
| A | Initial Release | M. Johnson | 12-Aug 2015 |
| - | Review and Write the suggestion to modify and update | Shawn/Mark/Dana | 27-Oct 2015 |
| B | Modified and Updated | AT | 18-April 2016 |